

ELECTIONS TO MEMBERSHIP

Individuals

Baras, John S., University of Maryland;
Barger, Samuel Floyd, Youngstown State University;
Berni, Betty, Wyatt Company, San Francisco, California;
Bhargava, Mira, State University of New York at Buffalo;
Bhaskaran, M., 140 Charles Street, Perth (6000), Australia;
Campbell, Donald A., Anderson College;
Chew, James F., Michigan State University;
Cinlar, Erhan, Northwestern University;
Cohen, Stanley, 2385 Barker Avenue, Apt. 2S, Bronx, New York;
Crain, Bradford R., University of Oklahoma;
Drew, Gaston G., 1230 Sherman Drive, Ottawa (5), Ontario, Canada;
Durling, Frederick C., University of Waikato, Hamilton, New Zealand;
Eby, B. Russell, Loma Linda University;
Fagan, James T., University of Florida;
Fiala, F., Carleton University;
Floyd, Denis R., Pahlavi University, Shiraz, Iran;
Frechette, Maurice, Spalding College;
Froeschl, Paul A., III., St Mary's College;
Fukami, Tetsuzo, Keio University, Yokohama, Japan;
Glaser, Marlene S., 4254 Hyacinth, Baton Rouge, Louisiana 70808;
Gosler, James Raymond, Clemson University;
Henley, Ruth Howard, Eastman Kodak, Rochester, New York;
Hirschorn, Ronald, Queen's University;
Hwang, Jun-Shung, Jackson St. College;
Jacobs, Glen K., Greenville TEC, Greenville, South Carolina;
Jafarian, Ali A., Arya-Mehr University, Tehran, Iran;
Kennel, C. W., University of Texas at El Paso;
Klingsberg, Paul R., University of Pennsylvania;
Kontogianes, John T., Southwestern College;
Kulkarni, Ravi, Columbia University;
Laszlo, Peter Alan, California State Polytechnic University;
Leslie, Patricia J., North Texas State University;
MacLean, Douglas W., University of Saskatchewan;
Mannix, C. E., Jr., North American Rockwell;
Masih, Samuel, Paine College, Augusta, Georgia;
Miller, Maurice Hugh, Jr., University of Alabama;
Molnar, Edward A., U.S. Army, Ft. Benjamin Harrison, Indiana;
Mozzochi, Charles Jeffrey, Marjel Corporation, Hartford, Connecticut;
Nelson, Abraham, Jr., Austin College;
Potluri, Venkata Rao, Reed College;
Reese, Howard Watson, Jr., Georgia Institute of Technology;
Richardson, John Francis, Rutgers University;